

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Young-pil Kim et al.

Serial No.: To Be Assigned

Filed: Concurrently Herewith

For: **Semiconductor Device Test Patterns and Related Methods for Precisely
Measuring Leakage Currents in Semiconductor Cell Transistors**

Date: March 9, 2004

Mail Stop Patent Application

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Sir:

Attached is a list of documents on Form PTO-1449, together with a copy of any listed foreign patent document and/or non-patent literature. A copy of any listed U.S. patent and/or U.S. patent application publication is not provided herewith in accordance with the waiver by the U.S. Patent and Trademark Office of requirements under 37 C.F.R. § 1.98(a)(2)(i) for all U.S. national patent applications filed after June 30, 2003 and for all international applications that have entered the national stage under 35 USC § 371 after June 30, 2003.

It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. § 1.56 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to Deposit Account No. 50-0220.

Respectfully submitted,



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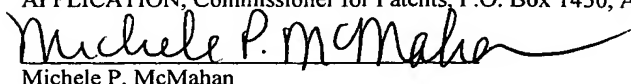
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Michele P. McMahan

Substitute form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet

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of

1

Complete if Known

Application Number

To Be Assigned

Filing Date

Concurrently Herewith

First Named Inventor

Young-pil Kim et al.

Group Art Unit

Unknown

Examiner Name

Unknown

Attorney Docket Number

5649-1276

U.S. PATENTS AND PATENT PUBLICATIONS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER NON PATENT LITERATURE DOCUMENTS

OTHER NON-PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T
	1	Young Pil Kim et al., "Reliability Degradation of High Density DRAM Cell Transistor Junction Leakage Current Induced by Band-to-Defect tunneling Under the Off-State Bias-Temperature Stress," <u>IEEE</u> , 2001	
	2	K. Saino et al., "Impact of Gate-Induced Drain Leakage Current on the Tail Distribution of DRAM Data Retention Time," <u>IEEE</u> , 2000	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.